

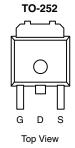
P-Channel 80-V (D-S) 175 °C MOSFET

PRODUCT SUMMARY V_{DS} (V) Q_g (Typ) $r_{DS(on)}(\Omega)$ $I_D(A)^a$ 0.0252 at V_{GS} = - 10 V - 50 - 80 55 nC 0.029 at V_{GS} = - 4.5 V - 47

FEATURES

• TrenchFET® Power MOSFET





Drain Connected to Tab

Ordering Information: SUD50P08-25L-E3 (Lead (Pb)-free)

P-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	- 80	V	
Gate-Source Voltage		V _{GS}	± 20	v	
Continuous Drain Current (T _J = 175 °C)	T _C = 25 °C		- 50 ^a	A	
	T _C = 70 °C		- 42.5 ^a		
	T _A = 25 °C	I _D	- 12.5 ^{b, c}		
	T _A = 70 °C		- 10.5 ^{b, c}		
Pulsed Drain Current		I _{DM}	- 40	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	,	- 50 ^a		
	T _A = 25 °C	I _S	- 6.9 ^{b, c}		
Avalanche Current	L = 0.1 mH	I _{AS}	- 45		
Single-Pulse Avalanche Energy	L = U.1 IIII	E _{AS}	101	mJ	
Maximum Power Dissipation	T _C = 25 °C		136	10/	
	T _C = 70 °C	P _D	95		
	T _A = 25 °C	LD	8.3 ^{b, c}	W	
	T _A = 70 °C		5.8 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS									
Parameter		Symbol	Typical Maximum		Unit				
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 sec	R _{thJA}	15	18	°C/W				
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	0.85	1.1	C/VV				

Notes:
a. Package limited.
b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 sec. d. Maximum under steady state conditions is 40 $^{\circ}\text{C/W}.$

SUD50P08-25L

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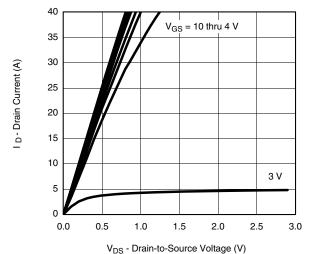
SPECIFICATIONS T _J = 25 °C, unless otherwise noted										
Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit				
Static										
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	- 80			V				
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 73		mV/°C				
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	10 = 200 μΑ		- 5.5						
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 3	V				
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA				
Zero Gate Voltage Drain Current	1	V _{DS} = - 80 V, V _{GS} = 0 V			- 1	μΑ				
	IDSS	V _{DS} = - 80 V, V _{GS} = 0 V, T _J = 55 °C			- 10					
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$				Α				
Drain-Source On-State Resistance ^a	r	V _{GS} = - 10 V, I _D = - 12.5 A		0.021	0.0252	Ω				
	r _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 10.5 A		0.024	0.029					
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 12.5 A		52		S				
Dynamic ^b										
Input Capacitance	C _{iss}			4700		pF				
Output Capacitance	C _{oss}	V _{DS} = - 40 V, V _{GS} = 0 V, f = 1 MHz		320						
Reverse Transfer Capacitance	C _{rss}	1		235						
		V _{DS} = -40 V, V _{GS} = -10 V, I _D = -12.5 A		105	160	nC				
Total Gate Charge	Q_g	V _{DS} = - 40 V, V _{GS} = - 4.5 V, I _D = - 12.5 A		55	85					
Gate-Source Charge	Q_{gs}			16						
Gate-Drain Charge	Q_{gd}]		26						
Gate Resistance	R_{g}	f = 1 MHz		4		Ω				
Turn-On Delay Time	t _{d(on)}			45	70	ns				
Rise Time	t _r	$V_{DD} = -40 \text{ V}, R_{L} = 3.8 \Omega$		220	330					
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 10.5 A, V_{GEN} = - 10 V, R_g = 1 Ω		95	145					
Fall Time	t _f	1		110	165					
Turn-On Delay Time	t _{d(on)}			15	25	ns				
Rise Time	t _r	$V_{DD} = -40 \text{ V, R}_{L} = 3.8 \Omega$		25	40					
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 10.5 A, $V_{GEN} =$ - 4.5 V, $R_g =$ 1 Ω		105	160					
Fall Time	t _f	-		100	150					
Drain-Source Body Diode Characteristic	es				l					
Continuous Source-Drain Diode Current	Is	T _C = 25 °C			- 50	А				
Pulse Diode Forward Current ^a	I _{SM}				- 40					
Body Diode Voltage	V _{SD}	I _S = - 10.5 A		- 0.8	- 1.2	V				
Body Diode Reverse Recovery Time	t _{rr}			55	85	ns				
Body Diode Reverse Recovery Charge	Q _{rr}	1 40.54 47/4 400.4/ 7 5-00		110	165	nC				
Reverse Recovery Fall Time	t _a	$I_F = -10.5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		37		ns				
Reverse Recovery Rise Time	t _b	1		18						

- a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.

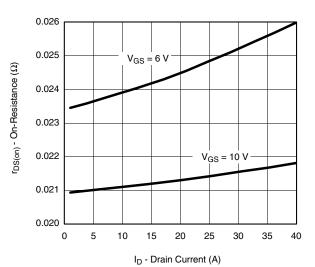
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



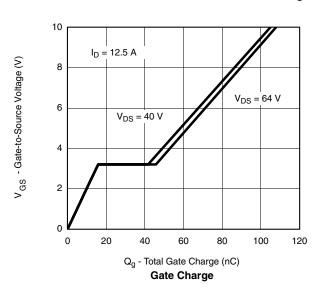
TYPICAL CHARACTERISTICS 25 °C unless noted



Output Characteristics

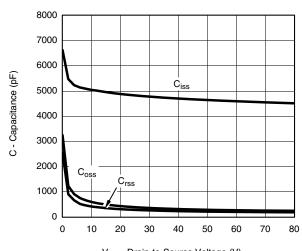


On-Resistance vs. Drain Current and Gate Voltage

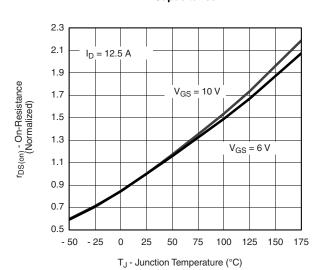


20 16 (V) the sum of the sum of

V_{GS} - Gate-to-Source Voltage (V) **Transfer Characteristics**



V_{DS} - Drain-to-Source Voltage (V) **Capacitance**



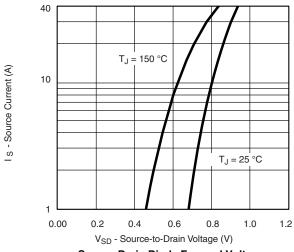
On-Resistance vs. Junction Temperature

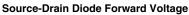
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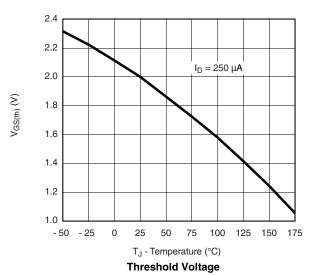
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TYPICAL CHARACTERISTICS 25 °C unless noted



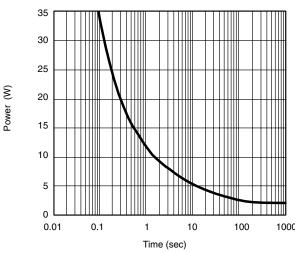




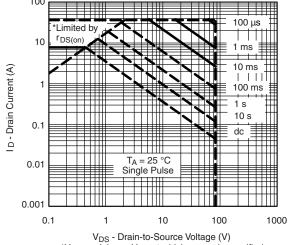


0.05 $r_{\text{DS(on)}}$ - Drain-to-Source On-Resistance (Ω) 0.04 T_A = 125 °C 0.03 $T_A = 25$ °C 0.02 0.01 2 3 6 9 10 V_{GS} - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

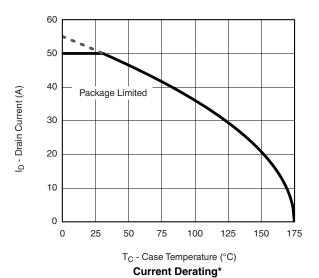


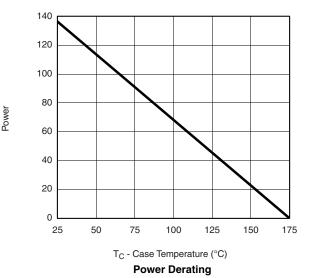
 $^*V_{GS}$ > minimum V_{GS} at which $r_{DS(on)}$ is specified

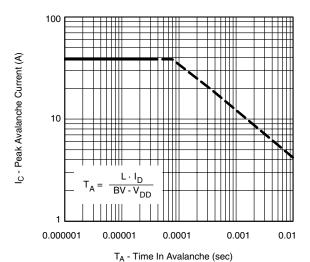
Safe Operating Area, Junction-to-Ambient



TYPICAL CHARACTERISTICS 25 °C unless noted







Single Pulse Avalanche Capability

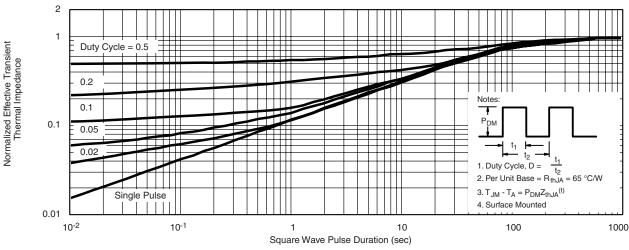
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^{*}The power dissipation P_D is based on $T_{J(max)}$ = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

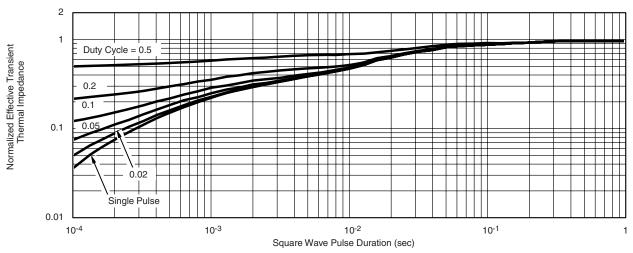




TYPICAL CHARACTERISTICS 25 °C unless noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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